Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/814,126	HSIANG, YUEH WEN		
Examiner	Art Unit		
David Q. Nguyen	2681		

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	569.1	1/17/05	W
381	315		
	330 86		
381 455	86		
455	575.2		
1	575.3		
455	535.6	417/8	m
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Eastseansh	u/rs/as	Dr	
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